

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10708730	HO ET AL.
	Examiner	Art Unit
	Detschel, Marissa J	2877

SEARCHED

Class	Subclass	Date	Examiner
356	328, 334	12/8/06	MJD

SEARCH NOTES

Search Notes	Date	Examiner
Updated EAST search from 5/5/06	12/8/06	MJD
Consulted Fannie Evans on allowable subject matter	1/11/07	MJD
Search terms: curved, concave, grating, path difference, arc length, groove, distance, position, slit, detector	1/4/07	MJD
Search Updated	6/07/2007	JC
Consulted Fannie Evans and Kara Geisel on allowable subject matter	6/07/2007	JC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
Interference searched	Searched above class/subclasses	6/07/2007	JC